

Notice of References Cited	Application/Control No. 10/762,621		Applicant(s)/Patent Under Reexamination HADLEY ET AL.	
	Examiner Gabriel L. Chu		Art Unit 2114	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-5,317,757	05-1994	Medicke et al.	712/229
*	C	US-5,539,680	07-1996	Palnitkar et al.	703/13
*	D	US-5,623,499	04-1997	Ko et al.	714/724
*	E	US-5,703,885	12-1997	Sun et al.	714/738
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NON-PATENT DOCUMENTS

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	V	Microsoft Press Computer Dictionary Third Edition, "block size", Microsoft Press, 1997, pg. 56.
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	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.